

# Variable resolution Associative Memory optimization and simulation for the ATLAS FastTracker project

Carmela Luongo

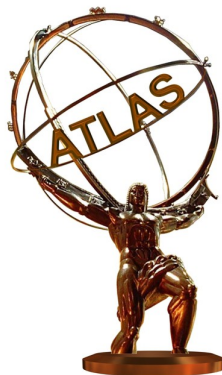
University and INFN Pisa



11th International Conference on Large Scale Applications and  
Radiation Hardness of Semiconductor Detectors  
In Florence, Italy 3-5 July

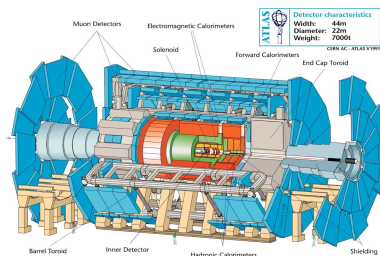
# Outline

- The FastTracker (FTK)
  - FTK for the ATLAS trigger upgrade
  - FTK algorithm
- Associative Memory (AM)
- Variable Resolution patterns
- Simulation studies
  - Multiple DC-bits study
  - HW constraints per pile-up events
  - Configurations
- Conclusions

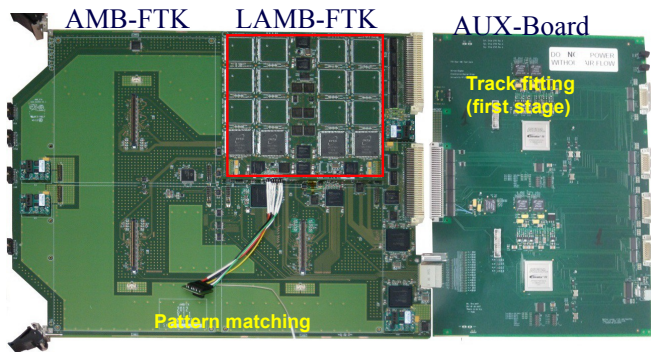


# FastTracker for the ATLAS trigger upgrade

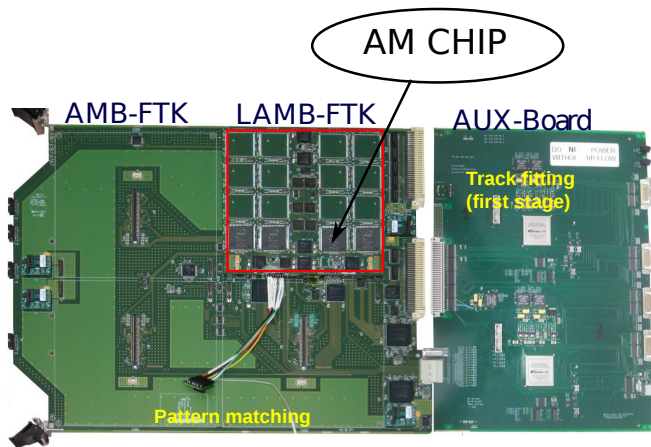
- FTK reconstructs charged particles trajectories in the silicon detectors (Pixel & SCT) at “1.5” trigger level.
- Extremely difficult task
  - 100 KHz processing rate
  - ~70 overlapping events (pile-up) at highest luminosity.



# FTK processing unit



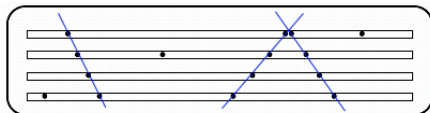
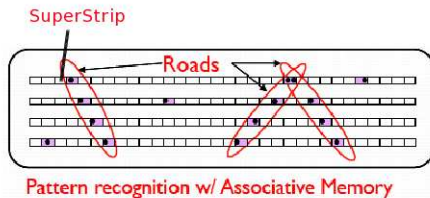
# FTK processing unit



# FTK algorithm

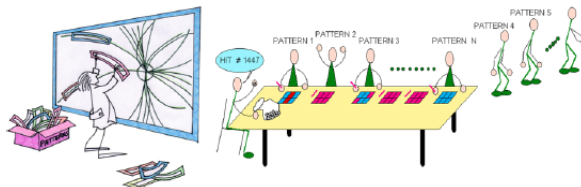
Two sequential steps:

- 1 Pattern recognition, carried out by a dedicated device called **Associative Memory** (AM). Find coarse-resolution track candidates called “roads”.  
Pattern recognition w/ Associative Memory
- 2 **Track Fitter** fits the full-resolution hits inside the road to determine the track parameters. Only the tracks passing the  $\chi^2$  cut are kept.



# AM working principle

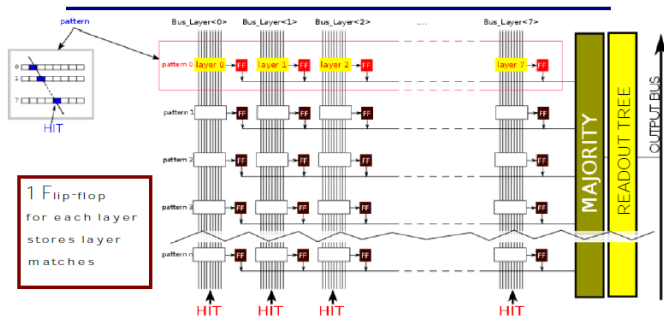
## AM = BINGO GAME



- player=pattern
- numbers on the card=bin
- extracted number=hit
- winning players=pattern matching

- Each pattern has its private HW to compare itself with the event
- Bingo game goes on until completion of detector readout
- All the winning patterns go to the output

# AM working principle

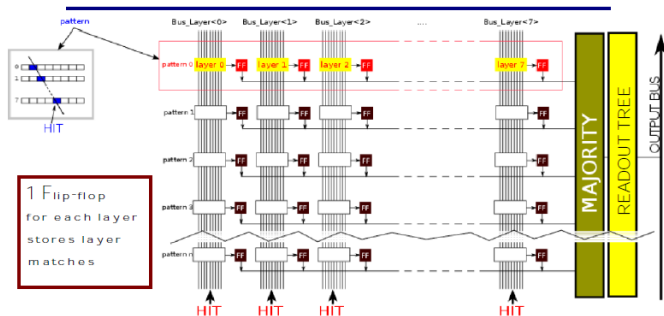


All patterns compared in parallel with incoming data. Look for correlation of data received at different times (feature unique to AM chip)



- Fast pattern matching
- Flexible input

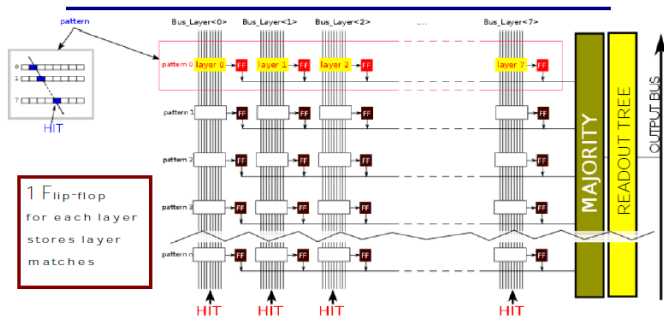
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- Fast pattern matching
- Flexible input

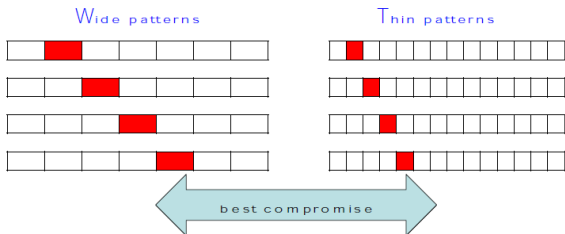
# Parameters to define the pattern-bank performance

## Pattern bank

Each track generates a hit pattern. The collection of all these patterns defines both the space of the tracks we are looking for and how they appear in the detector: this collection is the pattern bank

## Trade-off

Number of roads vs number of fits  $\Rightarrow$  critical parameter: road width



- Too wide  $\Rightarrow$  more fake roads  $\Rightarrow$  excessive work for the Track Fitter
- Too narrow  $\Rightarrow$  more AM patterns  $\Rightarrow$  too large cost

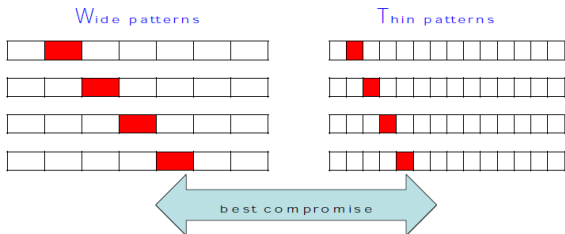
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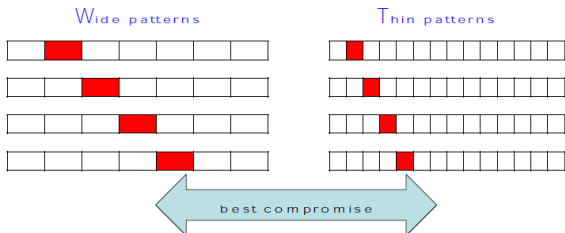
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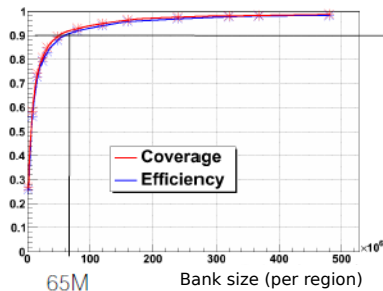
# Bank efficiency and # fakes at 69 pile-up events

Low resolution

SS=24 pixels in  $r\phi$

36 pixels in  $z$

20 strips in SCT



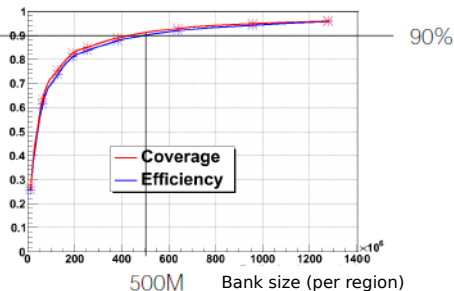
# ROADS/EVENT=342000

High resolution

SS=12 pixels in  $r\phi$

36 pixels in  $z$

10 strips in SCT



# ROADS/EVENT=40000

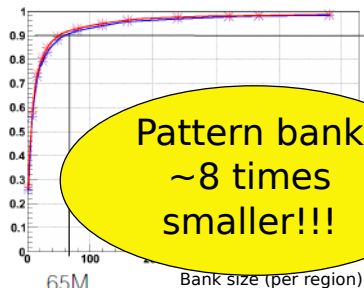
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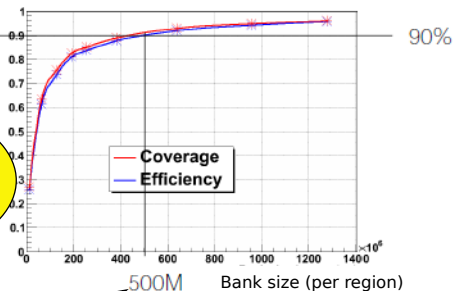
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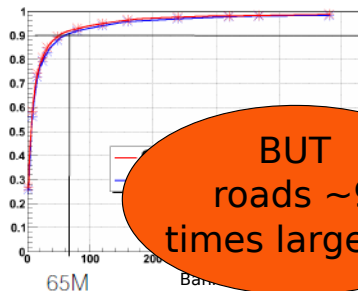
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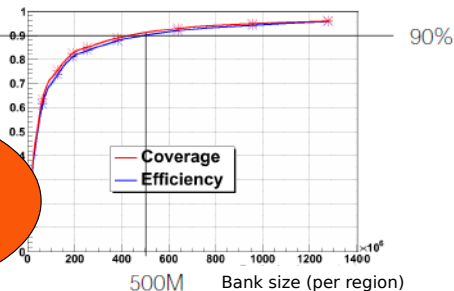


High resolution

SS=12 pixels in  $r\phi$

36 pixels in  $z$

10 strips in SCT



**BUT  
roads ~9  
times larger!!!**

# ROADS/EVENT=342000

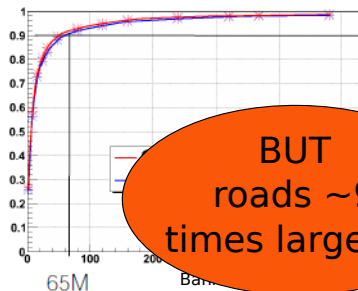


# ROADS/EVENT=40000



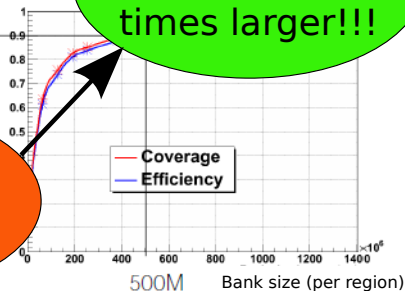
# Bank efficiency and # fakes at 69 pile-up events

Low resolution  
 SS=24 pixels in  $r\phi$   
 36 pixels in  $z$   
 20 strips in SCT



# ROADS/EVENT=342000

High resolution  
 SS=12



# ROADS/EVENT=40000

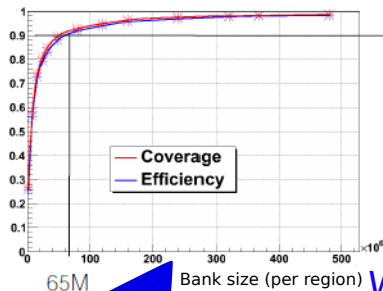
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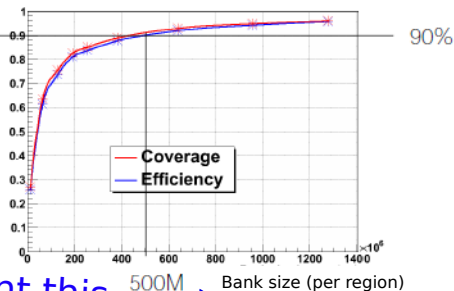


High resolution

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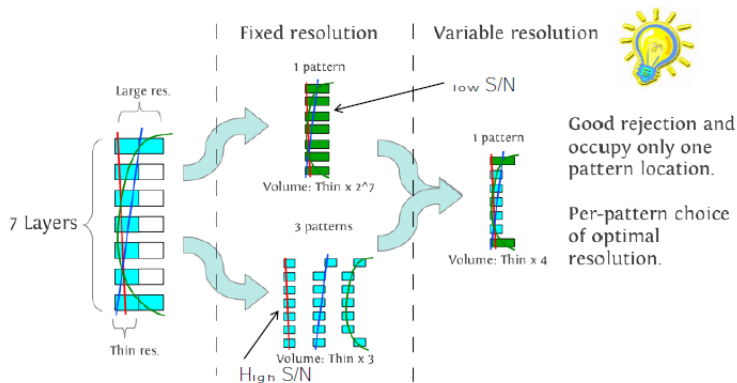


Want this

# ROADS/EVENT=342000

# ROADS/EVENT=40000

# Variable resolution patterns

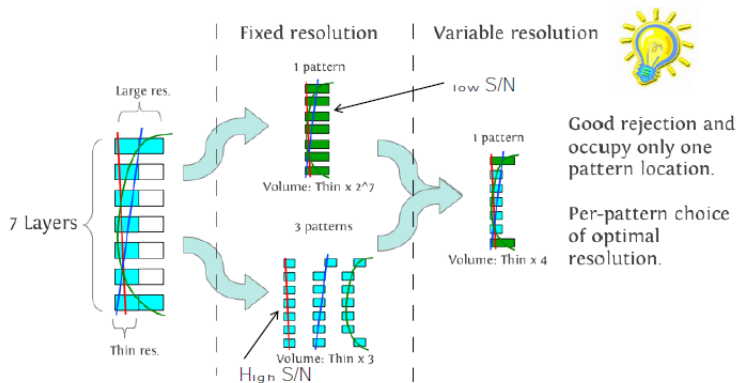


- Don't care (DC) on the least significant bit of hit position

⇒ Number of patterns within the HW limits

⇒ High rejection of fake roads

# Variable resolution patterns

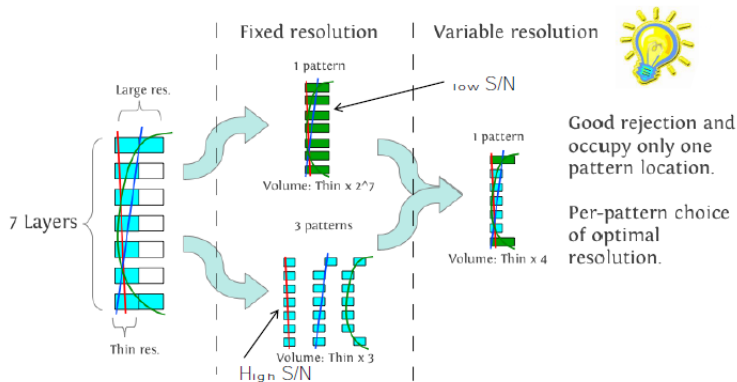


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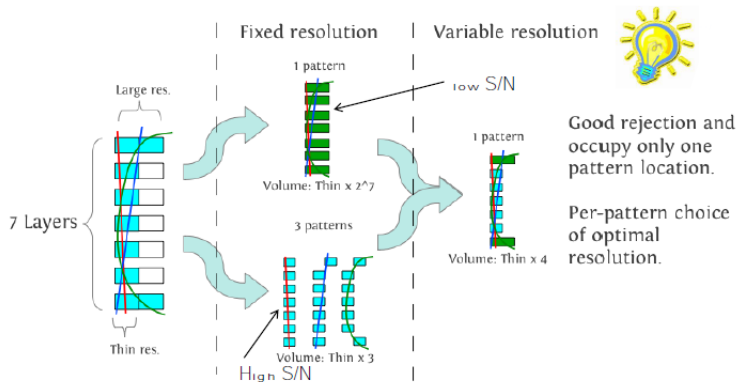


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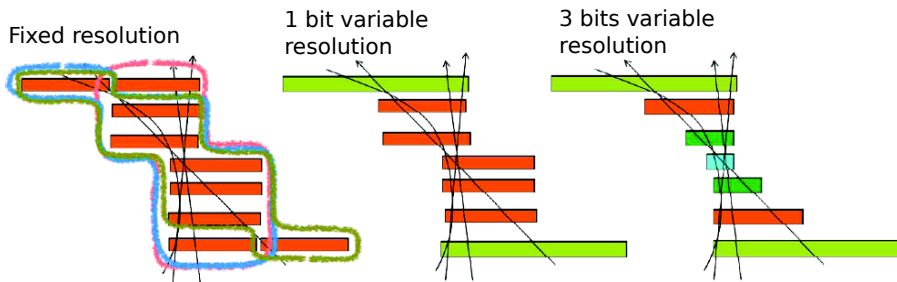


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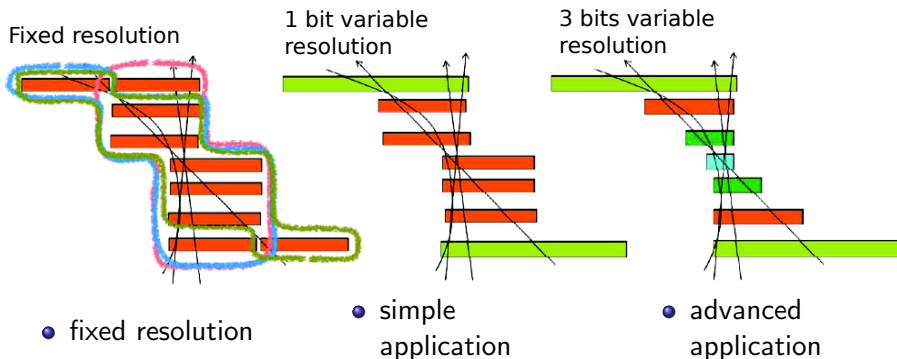
⇒ High rejection of fake roads

# Many bits variable resolution



- No variable resolution  $\Rightarrow$  3 patterns needed to accept the tracks
- Simple application  $\Rightarrow$  1 pattern needed to accept the tracks
- Advanced application  $\Rightarrow$  1 pattern needed but less volume

# Many bits variable resolution



Any coincidence based trigger can exploit this technique!

# Multiple DC bits study

## Goals

- Keeping high efficiency with a limited number of patterns
  - Limiting Track Fitter workload
- ⇒ Optimizing use of variable resolution patterns

## Main parameters

Number of patterns per track  
Track Fitter workload  
Track Fitter efficiency

# Multiple DC bits study

## Goals

- Keeping high efficiency with a limited number of patterns
- Limiting Track Fitter workload

⇒ Optimizing use of variable resolution patterns

## Main parameters

• Pattern bank size

• Number of seeds

• Number of tracks

• Number of hits

# Multiple DC bits study

## Goals

- Keeping high efficiency with a limited number of patterns
  - Limiting Track Fitter workload
- ⇒ Optimizing use of variable resolution patterns

## Main parameters

- Pattern bank size
- Number of nodes

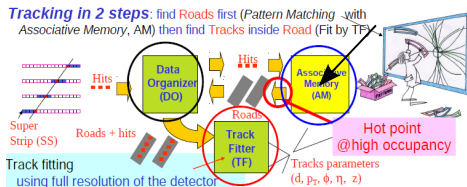
# Multiple DC bits study

## Goals

- Keeping high efficiency with a limited number of patterns
  - Limiting Track Fitter workload
- ⇒ Optimizing use of variable resolution patterns

## Main parameters

- Pattern bank size
- Number of roads
- Roads size
- Number of fits



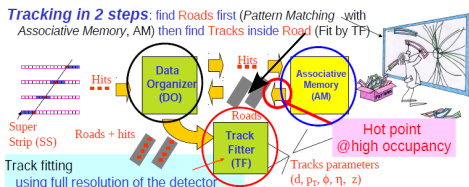
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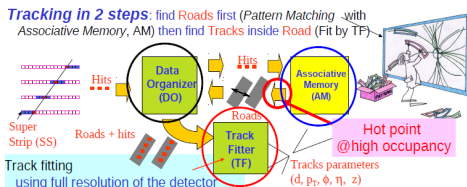
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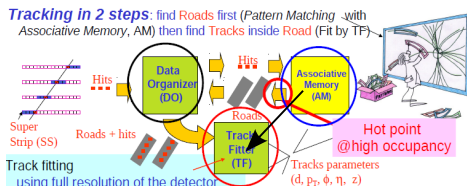
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## Goals

- Keeping high efficiency with a limited number of patterns
  - Limiting Track Fitter workload
- ⇒ Optimizing use of variable resolution patterns

## Main parameters

- Pattern bank size
- Number of roads
- Roads size
- Number of fits



# HW constraints for pile-up events

Maximum limits for each board:

- $8 \times 10^6$  patterns
- $8 \times 10^3$  roads
- $40 \times 10^3$  fits

Simulation results at 25 ns interbunch for 2015 and 2019:

- 1 46 pile-up events (2015): 16 boards working on 32 towers  
⇒ constraints for each tower:
  - $\#AMpatterns < 4 \times 10^6$
  - $\#Roads < 4 \times 10^3$
  - $\#Fits < 20 \times 10^3$
- 2 69 pile-up events (2019): 128 boards working on 64 towers  
⇒ constraints for each tower:
  - $\#AMpatterns < 16 \times 10^6$
  - $\#Roads < 16 \times 10^3$
  - $\#Fits < 80 \times 10^3$

# Configurations

- High resolution road:  $15 \times 36 \times 16$ 
  - $15 \times 36$  = number of pixels clustered in the same Super Strip ( $\phi \times z$ )
  - $16$  = number of strips clustered in the same Super Strip ( $\phi$ )
- Dataset with 69 pile-up events
- Constraints:
  - $\#AM < 16M \times 10^6$
  - $Roads < 16 \times 10^3$
  - $Fits < 80 \times 10^3$
- AM bank configurations:
  - 1  $(30 \times 36)_{pix} \times 32_{sct}$
  - 2  $(30 \times 72)_{pix} \times 32_{sct}$
  - 3  $(30 \times 144)_{pix} \times 32_{sct}$
  - 4  $(30 \times 72)_{pix} \times 64_{sct}$

⇒ Grouping larger number of the detector channels makes the SS granularity decrease

# Endcap - 69 pile-up events ( $\sim 2019$ )

DC bit	#AM $\cdot 10^6$	Efficiency(%) R=64	Roads/evt $\cdot 10^3$	Fits/evt $\cdot 10^3$	Tracks/evt
$(30 \times 72)_{pix \times 32_{sct}}$	18	91.2	7.1	56	106
$(30 \times 72)_{pix \times 32_{sct}}$	16.8	91.2	6.9	55	...
$(30 \times 72)_{pix \times 32_{sct}}$	15	91.0	6.2	50	...
$(30 \times 144)_{pix \times 32_{sct}}$	8	92.0	5	90	...
$(30 \times 72)_{pix \times 64_{sct}}$	8	93.0	9	154	...

**Table:** Results in endcap towers. #AM patterns, #Roads, #Fits and #Tracks are reported for one tower.

- The #Roads provides a measure of the fake roads
- The efficiency is evaluated on a single muon dataset (no pile-up)

# Endcap - 69 pile-up events ( $\sim 2019$ )

DC bit	#AM $\cdot 10^6$	Efficiency(%) R=64	Roads/evt $\cdot 10^3$	Fits/evt $\cdot 10^3$	Tracks/evt
$(30 \times 72)_{pix} \times 32_{sct}$	18	91.2	7.1	56	106
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**Table:** Results in endcap towers. #AM patterns, #Roads, #Fits and #Tracks are reported for one tower.

- For a given DC configuration:
  - Reducing the number of patterns reduces the number of roads and fits
  - Efficiency minimally reduced
  - Number of fake roads proportional to the bank size

# Endcap - 69 pile-up events ( $\sim 2019$ )

DC bit	#AM $\cdot 10^6$	Efficiency(%) R=64	Roads/evt $\cdot 10^3$	Fits/evt $\cdot 10^3$	Tracks/evt
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**Table:** Results in endcap towers. #AM patterns, #Roads, #Fits and #Tracks are reported for one tower.

- The power of the variable resolution pattern
  - Increased efficiency and reduced roads number
  - Half size bank!

# Barrel - 69 pile-up events ( $\sim 2019$ )

DC bit	#AM $\cdot 10^6$	Efficiency(%) R=64	Roads/evt $\cdot 10^3$	Fits/evt $\cdot 10^3$	Tracks/evt
$(30 \times 72)_{pix} \times 32_{sct}$	21	94.8	3.9	33	42
$(30 \times 72)_{pix} \times 32_{sct}$	18	94.1	3.4	28	38
$(30 \times 72)_{pix} \times 32_{sct}$	16.8	93.3	3.2	26	36
$(30 \times 144)_{pix} \times 32_{sct}$	8	95.0	4	60	...
$(30 \times 72)_{pix} \times 64_{sct}$	8	96.0	6	98	...

**Table:** Results in barrel towers. #AM patterns, #Roads, #Fits and #Tracks are reported for one tower.

# Work in progress - 46 pile-up events ( $\sim 2015$ )

- Exploring better initial road resolutions and larger number of DC bits
- High resolution road:  $11 \times 18 \times 12$ 
  - $11 \times 18$  = number of pixels
  - $12$  = number of strips
- We are trying some DC-bits bank configurations:
  - $(22 \times 72)_{pix} \times 24_{sct}$
  - $(44 \times 72)_{pix} \times 48_{sct}$
  - $(44 \times 144)_{pix} \times 48_{sct}$
- We will have the efficiency, roads, and tracks numbers soon

# Conclusions

- We have simulated complex configurations of the powerful variable resolution pattern-matching
  - The patterns are able to change in shape and matching volume
  - The “don’t care” bit improves the precision only where needed
  - High rejection of fake roads  $\Rightarrow$  the number of roads out of the AM chip is reduced greatly by using the variable resolution patterns
  - High compression factor in case of similar patterns  $\Rightarrow$  the number of patterns in the AM chip is significantly reduced

Thanks to the variable resolution implementation we are able to set the architecture parameters so that all HW constraints are satisfied.